SDAS083B - APRIL 1982 - REVISED DECEMBER 1994

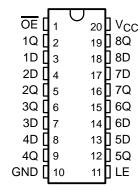
- Eight Latches in a Single Package
- 3-State Bus-Driving True Outputs
- Full Parallel Access for Loading
- Buffered Control Inputs
- pnp Inputs Reduce dc Loading on Data Lines
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

These octal transparent D-type latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

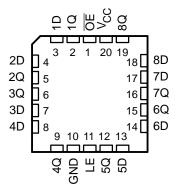
While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

SN54ALS373, SN54AS373 . . . J PACKAGE SN74ALS373A, SN74AS373 . . . DW OR N PACKAGE (TOP VIEW)



SN54ALS373, SN54AS373 . . . FK PACKAGE (TOP VIEW)



OE does not affect internal operations of the latches. Old data can be retained or new data can be entered while the outputs are off.

The SN54ALS373 and SN54AS373 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS373A and SN74AS373 are characterized for operation from 0°C to 70°C.

## FUNCTION TABLE (each latch)

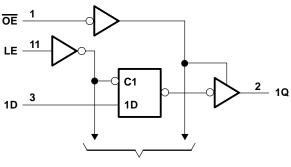
	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	$Q_0$
Н	X	Χ	Z

SDAS083B - APRIL 1982 - REVISED DECEMBER 1994

#### logic symbol†

#### OE ΕN LE C1 2 1D 1D 1Q 5 4 2Q 2D 6 7 3D 3Q 8 9 4D 4Q 13 12 5D 5Q 14 15 6D 6Q 17 16 7D 7Q 18 19 8D 8Q

#### logic diagram (positive logic)



To Seven Other Channels

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Voltage applied to any output in the high state or power-off state	5.5 V
Operating free-air temperature range, T <sub>A</sub> : SN54ALS373	−55°C to 125°C
SN74ALS373A	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		SN	54ALS3	73	SN7	4ALS37	3A	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
loL	Low-level output current			12			24	mA
t <sub>W</sub>	Pulse duration, LE high	12			10			ns
t <sub>su</sub>	Setup time, data before LE↓	10			10			ns
th	Hold time, data after LE $\downarrow$	7			7			ns
T <sub>A</sub>	Operating free-air temperature	-55		125	0		70	°C



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SDAS083B - APRIL 1982 - REVISED DECEMBER 1994

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	TEST CONDITIONS		54ALS3	73	SN74ALS373A			UNIT
PARAMETER	1231 (	UNDITIONS	MIN	TYP <sup>†</sup>	MAX	MIN	TYP†	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_1 = -18 \text{ mA}$			-1.5			-1.5	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2	2		V <sub>CC</sub> -2	2		
Voн	V <sub>CC</sub> = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.4	3.3					V
	VCC = 4.5 V	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
Voi	V 45V	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 24 mA					0.35	0.5	V
lozh	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			20			20	μΑ
lozL	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0.4 V			-20			-20	μΑ
I <sub>I</sub>	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 7 V			0.1			0.1	mA
liн	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 2.7 V			20			20	μΑ
I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.1			-0.1	mA
lo <sup>‡</sup>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-20		-112	-30		-112	mA
		Outputs high		9	16		9	16	
lcc	V <sub>CC</sub> = 5.5 V	Outputs low		16	25		16	25	mA
		Outputs disabled		17	27		17	27	

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C <sub>l</sub> R1 R2	_ = 50 pl l = 500 Ω 2 = 500 Ω	2,	,	UNIT
			SN54ALS373		SN74ALS373A		
			MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	D	•	2	17	2	12	ns
t <sub>PHL</sub>	D	Q	1	19	4	16	115
t <sub>PLH</sub>	LE	A O	6	29	6	22	ns
t <sub>PHL</sub>	LC	Any Q	1	27	7	23	115
<sup>t</sup> PZH		A 0	6	22	1	18	
tPZL	ŌĒ	Any Q	5	24	5	20	ns
<sup>t</sup> PHZ	ŌĒ	Any Q	2	16	1	10	
<sup>t</sup> PLZ	OE .	Ally Q	2	24	2	12	ns

<sup>§</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



<sup>&</sup>lt;sup>‡</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS083B - APRIL 1982 - REVISED DECEMBER 1994

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	$\dots \dots $
Input voltage, V <sub>I</sub>	$\dots \dots $
Voltage applied to any output in the high state or power-off state	5.5 V
Operating free-air temperature range, T <sub>A</sub> : SN54AS373	. −55°C to 125°C
SN74AS373	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		SI	N54AS37	3	SN	174AS37	3	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-12			-15	mA
IOL	Low-level output current			32			48	mA
t <sub>W</sub> *	Pulse duration, LE high	5.5			4.5			ns
t <sub>su</sub> *	Setup time, data before LE↓	2			2			ns
th*	Hold time, data after LE↓	3			3			ns
TA	Operating free-air temperature	-55		125	0		70	°C

<sup>\*</sup> On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST C	ONDITIONS	SN54AS373		'3	SN74AS373			UNIT
PARAMETER	1231 C	ONDITIONS	MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT
VIK	$V_{CC} = 4.5 V,$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I <sub>OH</sub> = −2 mA	VCC -2	2		V <sub>CC</sub> -2	2		
$V_{OH}$	V 45 V	$I_{OH} = -12 \text{ mA}$	2.4	3.2					V
	V <sub>CC</sub> = 4.5 V	$I_{OH} = -15 \text{ mA}$				2.4	3.3		
Va	V 45V	$I_{OL} = 32 \text{ mA}$		0.27	0.5				V
VOL	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA					0.32	0.5	V
lozh	$V_{CC} = 5.5 V$ ,	V <sub>O</sub> = 2.7 V			50			50	μΑ
l <sub>OZL</sub>	$V_{CC} = 5.5 V$ ,	V <sub>O</sub> = 0.4 V			-50			-50	μΑ
lj	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 7 V			0.1			0.1	mA
lіН	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 2.7 V			20			20	μΑ
I <sub>IL</sub>	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 0.4 V		-0.02	-0.5		-0.02	-0.5	mA
ΙΟ§	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	-30		-112	mA
		Outputs high		55	90		55	90	
ICC	V <sub>CC</sub> = 5.5 V	Outputs low		55	85		55	85	mA
		Outputs disabled		65	100		65	100	

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>§</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



# SN54ALS373, SN54AS373, SN74ALS373A, SN74AS373 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS SDAS083B – APRIL 1982 – REVISED DECEMBER 1994

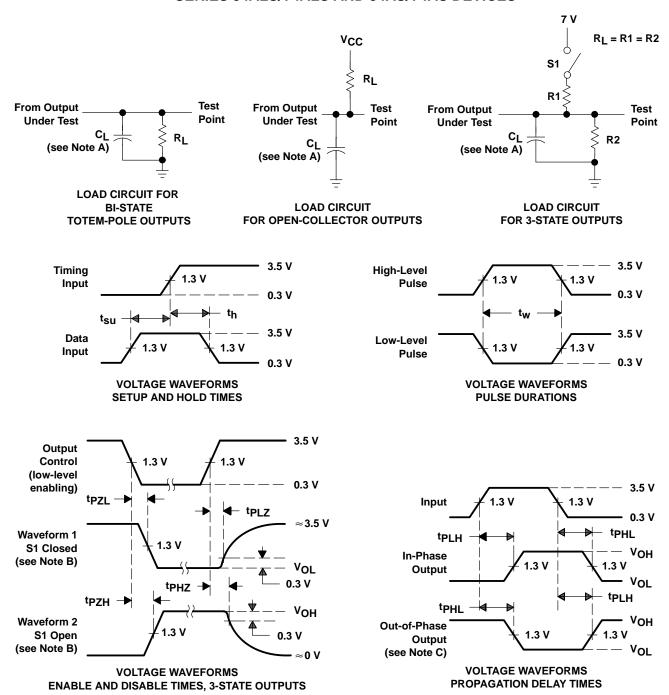
#### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C <sub>l</sub> R1 R2	= 50 pF   = 500 Ω   = 500 Ω	2,	,	UNIT
			SN54AS373				
			MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	D	•	3	9	3.5	6	ns
<sup>t</sup> PHL	D	Q	3	8	3.5	6	115
<sup>t</sup> PLH	LE	A O	6.5	14.5	6.5	11.5	ns
<sup>t</sup> PHL		Any Q	5	9	5	7.5	110
<sup>t</sup> PZH	ŌĒ	A O	2	7.5	2	6.5	20
<sup>t</sup> PZL	] OE	Any Q	4.5	10.5	4.5	9.5	ns
<sup>t</sup> PHZ	ŌĒ	Any O	3	10	3	6.5	20
<sup>t</sup> PLZ	OE	Any Q	3	8	3	7	ns

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

SDAS083B - APRIL 1982 - REVISED DECEMBER 1994

# PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz,  $t_f = t_f = 2$  ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



#### **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated